



GLAST Large Area Telescope Calorimeter Subsystem

5.3 CDE Manufacturing

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CEA responsibilities

Design and development of the CDE including:

- CDE process specification (written & sent for call for tender Feb'03)
- shared procurement, with the U.S., of DPDs to a common specification (1800 DPD from CEA-Hamamatsu-France proposition Mar'03)
- DPD testing (done for EM-DPDs)
- procurement of DPD wires, attachment and testing of the PDA (diode-cable assemblies),
- bonding of PDA to the Crystals and process qualification,
- procurement of wrapping material, crystal wrapping, and process qualification,
- acceptance testing of finished CDE





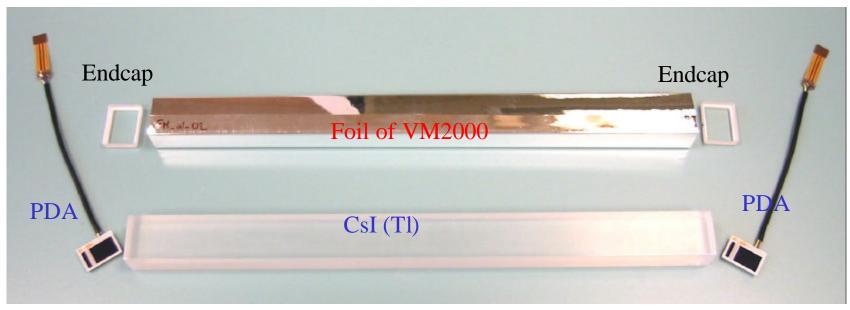
Program status

- □ LoA between NASA and CNES
 - final draft approved by both parties, almost signed
- MoA between SLAC, NRL, CEA:
 - signed in Jan'03
- □ Financial agreement between CNES and CEA:
 - budget & manpower profiles approved in Nov'02
 - new CNES financial situation: participation to GLAST recommended to the President, but cost-capped
- □ 14 EM-CDEs delivered to NRL in Dec'03
 - they meet the specifications & performance
 - bonding on DPD (epoxy window) & tooling design demonstrated
 - packing concept evaluated
 - DPD evaluation failed (epoxy window at low T + pin corrosion) P new DPD
 - flex changed to wires at the CAL level
- present activities
 - evaluation of the new DPD, new PDA and new PDA bonding
 - placing contracts for the FM PDA, CDE, GSE, & various containers





CDE Overview



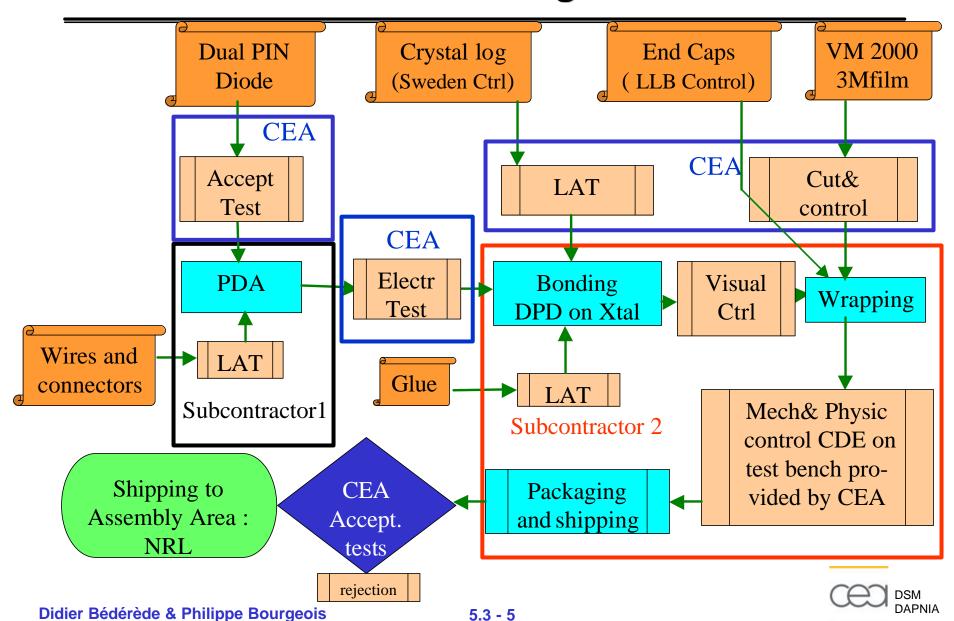
□ a CDE consists of :

- 1 cristal log of Csl doped with Thallium provided and tested by Sweden
- 2 PDA (DPD with wires), one bonded to each end
- wrapping consisting of one molded foil of VM2000 and 2 white endcaps provided and controlled by LLR





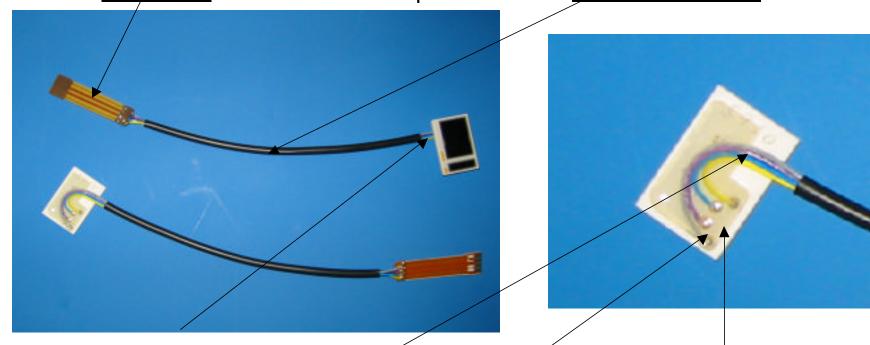
Manufacturing Plan



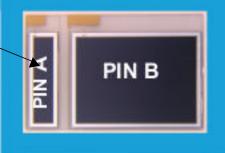


PDA overview

PDAfr = Connector for all French acceptance tests + Protective sleeve + PDA



PDA = Dual Pin Diode +4 wires (colour coded) soldered on pins+ staking







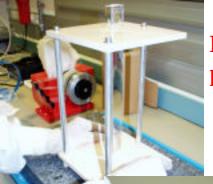
PDA manufacturing plan

- □ Because of the short schedule: wire procurement before contract (> 8 weeks to manufacture)
- □ Contract Order: foreseen May 21
 - Call for tender : done (6 companies interested)
 - Sending specifications to selected companies (mid March)
 - Answers from the companies: (end April)
 - Opening letters and ask for additional information
 - Write & sign the contract and place the order
- Preparation &training (molding tools, encapsulant product...)7 weeks
- Manufacturing lot 1 of 264 PDA (begin. July to begin. Aug)
- Manufacturing lot 2 of 240 PDA (in August)
- Manufacturing lots 3 to 20 (240 PDA /2 weeks)





PDA-Crystal Bonding Process Overview



End face polishing **Mold tooling & Glue injection**

Mold removal after 24 hours

Support tooling





Polymerisation time = 7 days





Wrapping overview

VM2000 foil wrapped and pasted **VM2000** foil shaped around a kernel at 120°C Mounting of the end cap around DPD Wrapped **CDE**



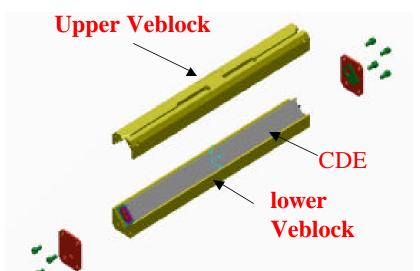
CDE manufacturing plan

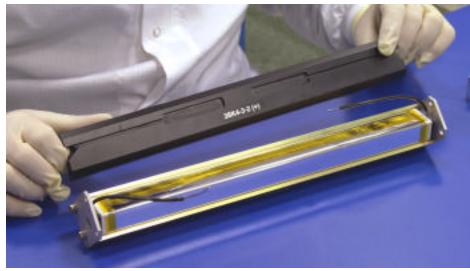
- □ Same manufacturer does bonding & wrapping
- Order foreseen May 26
 - Call for tender : done (6 companies interested)
 - Sending specifications to selected companies: done Feb. 13
 - Answers from the companies: March 28
 - Opening letters and ask for additional information < 2 weeks
 - Company selection, presentation of documents to comittee on 20 May
 - Write & sign the contract and place the order 10 days
- Procurement of toolings to manufacture 60 CDE/week, process practice & tuning on CEA tooling, tests on mini-Xtal, tests of 12 CDE: 3 months
- Manufacturing&acceptance lot 1: 120 CDE in 4 weeks in Sept
- Manufacturing&acceptance lots 2 to 17: 108 CDE/2 weeks Mid May '04





CDE packing & shipping













CDE System/Verification plan

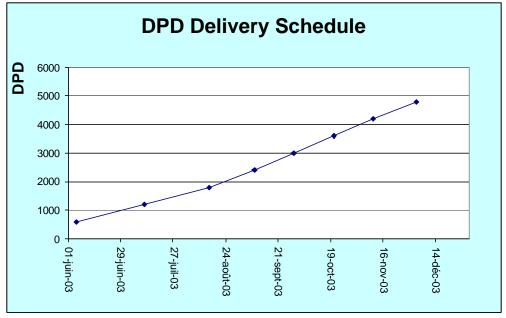
- EVALUATION: characteristics and margin studies
 - DPD S8576-01 (Silicone window, Lead tinning):
 - 11 S8576 with Silicone encapsulant
 - 184 S8576-01 (DPD pre-FM-series)
 - PDA (solder, staking, wires): DPD pre-series
 - Bonding (tooling, process): DPD pre-series + mini Xtal
- □ QUALIFICATION: Specification requirements
 - DPD S8576-01
 - Tinned ceramic: 1% by lot
 - **Die:** 5 by wafer lot
 - Assembly: 10% 1^{rst} Delivery Lot (+ screening)
 - PDA (Plan TBC)
 - Bonding (tooling, process): DPD pre-series + mini Xtal
 - CDE : DPD pre-series+ Xtal pre-series





DPD procurement status

- □ New DPD version: S8576-01
- □ Order shared between NRL (5 lots) and CEA (3 lots)
- Order in place before evaluation (driven by schedule)
- Delivery of a pre-series:
 - 184 with the silicone resin encapsulant
 - 20 without encapsulant (backup encapsulent study)
- □ **Delivery by Lot of 600 DPD:** Qualification on 1st lot







DPD Qualification plan

□ Philosophy:

- Qualification on 1 lot associated to a screening
- Qualification on 60 of 1st Delivery Lot in addition to its Acceptance test

□ Main tests

- Lead solderability (1 DPD)
- Moisture intake (168h, 50°C, 50%RH) (6 DPD)
- Steady-state life (1000h, 60°C) (22 DPD)
- Thermal cycle (60c, -30 to 50°C) (10 DPD)
- Radiation testing (10krad) (3 DPD)

□ Associated control

- Dark current & Green photosensitivity
- Delamination, crack
- Destructive Physical analysis





DPD Acceptance Test (1)

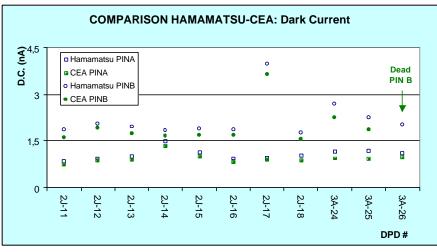
- Receiving inspection (with Hamamatsu representative)
 - Packaging and sensor inspections (shock, humidity, temp.)
 - DPD recorded parameters vs the acceptance limits
 - D.C., Capacitance, Sensitivity
- □ Control (within 2 weeks at CEA)
 - 100% Visual inspection (window, leads)
 - ⇒ refusal of bad DPDs
 - Sampling > 10% parameters (D.C., Capacitance, Sensitivity)
 - Drift production monitoring
 - ⇒ Refusal of the delivery lot

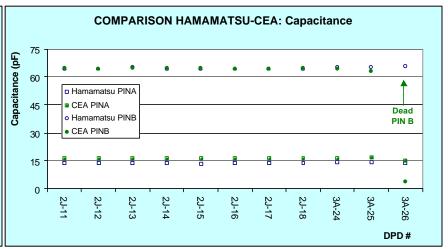


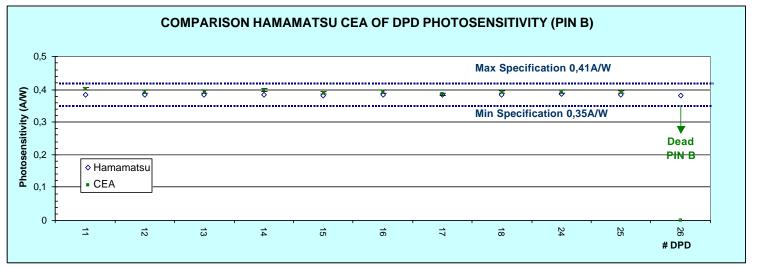


DPD Acceptance Test (2)

Acceptance test on the 11 DPD S8576 Silicone window









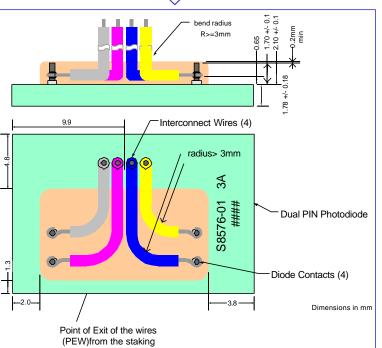


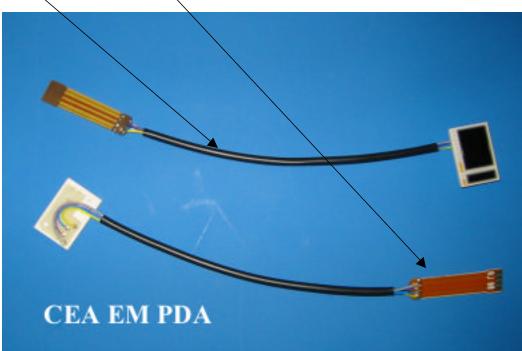
PDA design

PhotoDiode Assembly: DPD + soldered wires + wires staking on ceramic

PDAfr: PDA + protective sleeve + connector for CEA test benches

New lead position of S8576-01 New staking mold





New connector





PDA verification plan

□ Evaluation:

- Strength of the soldered and staked wires (1kg requirement)
- New tinning (SN96Ag4 + 40°C) study of DPD temperature when soldering
- Insulation of the 0.2mm staking above the leads (0.1nA)

□ Qualification:

- Spatial components (wires, encapsulant)
- Spatial approve Subcontractor
- Thermal cycle (60c, -30 to 50°C) study of lead insulation on bare ceramic

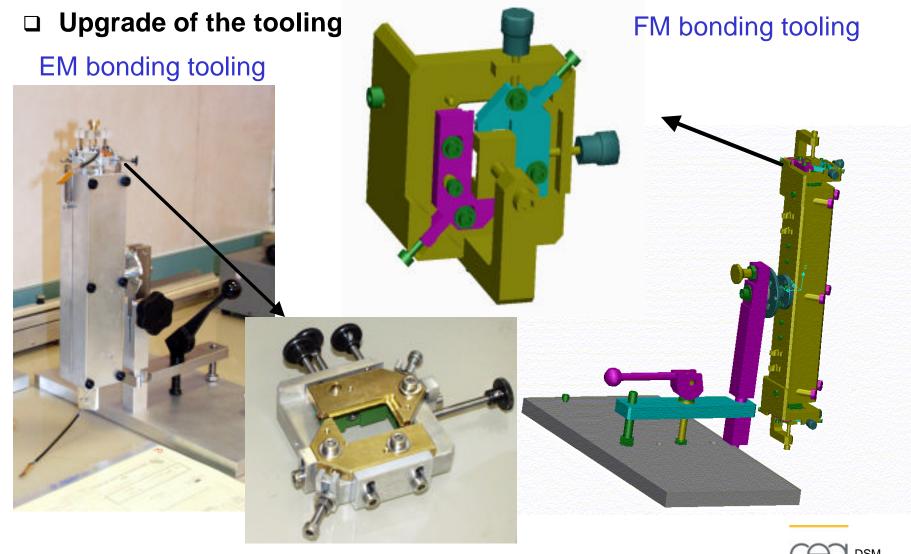
□ Acceptance test:

- 100% Electrical (D.C.)
- 100% Visual (Solder before staking, window)
- 100% go-no go staking area
- 100% staking thickness





Bonding tooling design





Bonding process verification

- □ Sample: Mini Xtal + PDA at each end
- Evaluation:
 - Thermal Cycle (-30 to 50°C, -38 to 60°C & -45 to 70°C, 30 cycles)
 - Mechanical Test (Shearing, shock, pulling)
 - Optical test (light yield)
- Qualification:
 - 1. Tooling and procedure
 - Thermal Cycle (-30 to 50°C, 0-30-60 cycles)
 - Mechanical Test (only Shearing)
 - Optical test (light yield)
 - 2. Sub-contractor
 - Same plan
- □ Acceptance test:
 - 2 samples every 100 bonding
 - 100% Visual inspection (bubble)

⇒ repair allowed but PDA lost





Wrapping foils inspection and testing

- □ VM2000 roll Acceptance:
 - Reflectivity measurement
 - Wrapping of a reference CDE for L.Y. measurement
- □ VM2000 cutting Acceptance:
 - Clean room environment (Class 100,000)
 - Packaging by 12 sheets (with traceability)
 - 1 sheet every 120 for L.Y. control on ref CDE





CDE Wrapping Tooling design

□ Based on Swales design and procedure

Upgrade of the molding tooling for a better reliability of the

sheet position

VM2000 Mold tooling (120°C, 2h)





Industrialization of the Wrapping tooling

Wrapping tooling

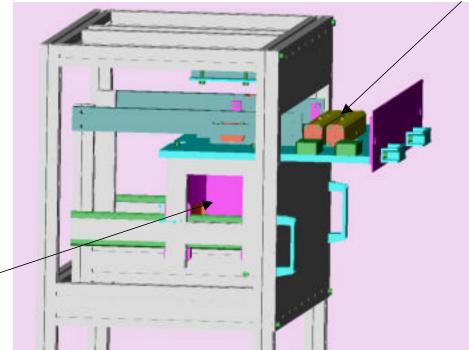




CDE Verification Plan (1)

- □ TEST at the subcontractor
 - 100% mechanical control
 - 100% PIN B L.Y. and resolution; PIN B/PIN A ratio

2 CDE at the time in their V support



Yttrium 1.84MeV γ radioactive source

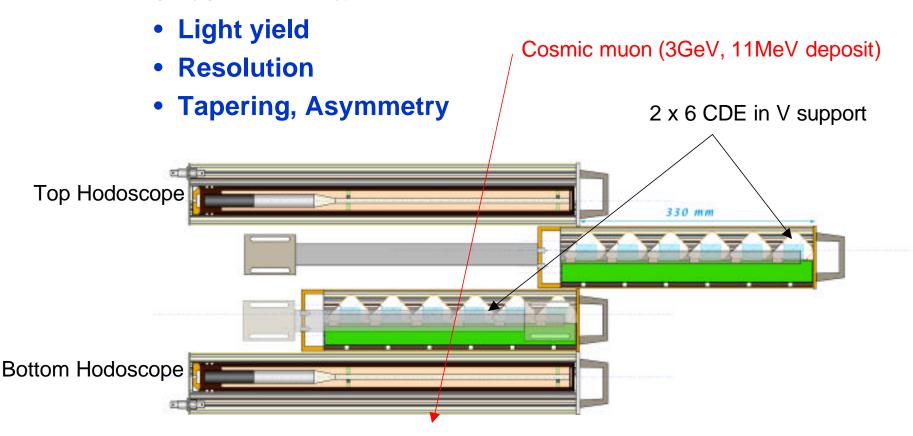
BIG (Banc Industrie Glast)





CDE Verification Plan (2)

- □ Performance measurements before shipping to NRL
 - For both PIN A & B:



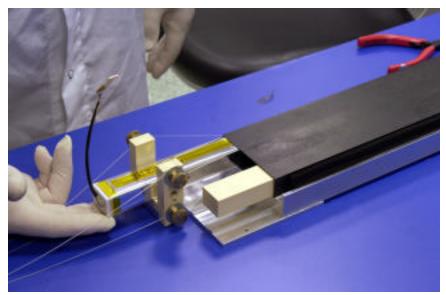
BCG (Banc Cosmiques Glast)





CDE Verification Plan (3)

- Insertion test before shipping to NRL
 - Go no go: Minimum size Cell + 1mm cord stretched by a factor 2
 - If no go ⇒ Go-no go: Mean size Cell
 - Study of a two piecesAluminium Alloy Cell



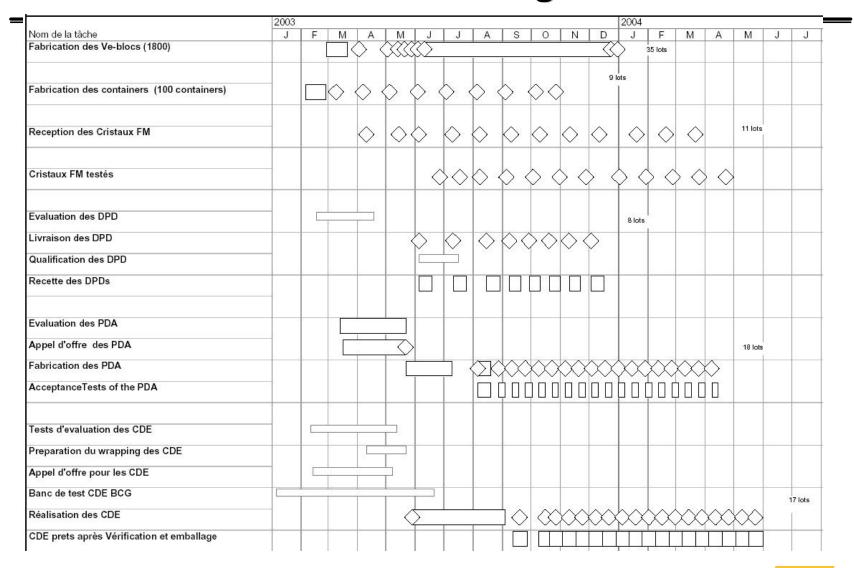
Qualification

- Thermal Cycle (-30 to 50°C, 0-30-60 cycles)
- Vacuum (-1000mBar in 100s)
- Radiation test (10kRad)



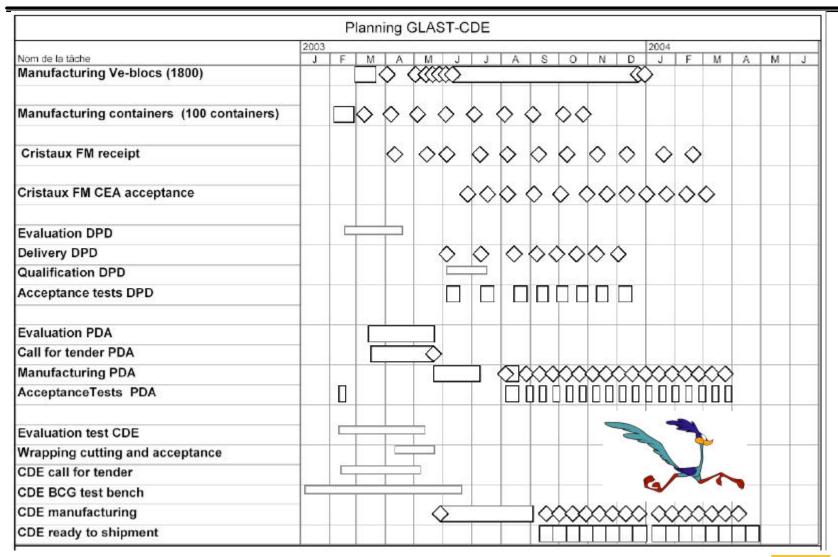


Current manufacturing schedule





Increased rate schedule



Manpower & financial impact under study (60 CDE/week)





Schedule risks

- Current schedule very tight
 - assumes successful DPD evaluation, PDA qualification, & bonding qualification
 - Market Committee Review (Budget Ministry & CEA): if review requested ⇒contract starting date could shift from May 26 to June 20 Mandatory
 - Manufacturers may be uncomfortable with 3 month preparation time and ask for 4 months known on March 31
- □ Increased rate schedule
 - Cost impact evaluated by March 31
 - Rate = 60/week ⇒last CDE on time
 - Rate = 80/week ⇒ FM4 -16 on time





Issues/Concerns

- New DPD evaluation
 - in progress on 10 samples
 - on some of the 184 DPDs starting in April
- □ DPD qualification on 60 DPD of lot 1 (= 600)
 - many manufactured by then P risk on schedule & cost
- PDA qualification of the soldering & staking
 - on some of the 184 DPDs starting in April
- Bonding qualification (concave silicon window)
 - tests at NRL, 4 being tested at Saclay, more in April
- □ Wrapping : VM2000 ESD properties
 - in progress at NRL and Goddard
- □ DPD packaging to be improved (in progress)
- No absolute light yield requirement on the Xtal, but on the CDE
 - Action: L.Y. acceptance tests of Xtals with DPD and sources

